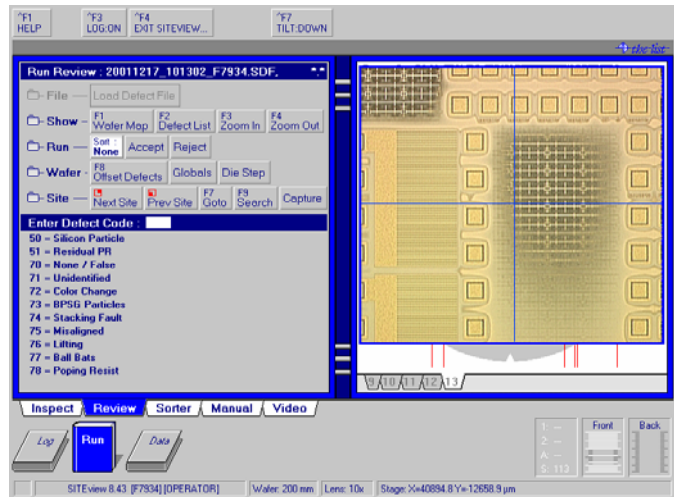


### Applications Include:

- ▶ Visual Inspection
- ▶ Defect Review
- ▶ OCR
- ▶ Sorting
- ▶ Second Optical Inspection
- ▶ Image Storage & Retrieval
- ▶ Overlay Measurement
- ▶ Laser Marking
- ▶ GEM/SECS II
- ▶ Host Communication – LAN
- ▶ UV Microscope Interface



### SITEview™ is a True user-oriented optical inspection and metrology package:

- ▶ Single screen operations eliminate screen clutter
- ▶ Multi-level password protection
- ▶ User customizable screen appearance, buttons & functions
- ▶ Recipe's created on or offline are available to all systems via Host (LAN) connection
- ▶ One software version for all systems & configurations for 50mm – 300mm wafers

### OCR & Sorting

- ▶ Front or Backside scribe
- ▶ Inventory file stores wafer history by ID AND Slot, Lot log in / out time & date, duration at each inspection point, wafer or defect classification
- ▶ Enables full sorting functions – Move, Compress, Randomize, Find, Align, Verify and Split Lot.

### Defect Review

- ▶ Compatible with all defect file types
- ▶ Cassette BCR operation automatically loads defect file
- ▶ View Defect Map, Defect List, Defect Live or Stored Image
- ▶ Auto-Defect Search routine, Defect Offset, Binning, user definable defect code list and one click defect image storage

### Second Optical Inspection

- ▶ Download probe test file
- ▶ Siteview creates good/bad Die wafer map and generates “S” scan at selected Die for review. Can enter defect codes
- ▶ OCR # and defect data is appended to original file and sent to Host

### Overlay Metrology

- ▶ Incorporate “Box in Box” or “Frame in Frame” Overlay measurements within a visual inspection recipe
- ▶ Automated measurements with pattern recognition used for global and local alignment

### LAN Interface

- ▶ Recipe's & Images are stored on a Host computer. If connection is lost, system will work from local drive and automatically switch to Host when connection is restored

### Easy Robot Setup – Detailed Diagnostics

- ▶ Easy to use GUI service interface simplifies diagnostics and provides an automated robot teach routine for each wafer exchange position.
- ▶ **SITEview™** provides an easy upgrade path for existing LEP MAC 2000 based systems